

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY DOCKET NO. 03500.017136.		APPLICATION NO. 10/656,242	
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				APPLICANT NOBUHIRO YASAI, ET AL.			
JUL 18 2005 U.S. PATENT DOCUMENTS				FILING DATE September 8, 2003		GROUP 1773	


EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
HLL	US 2004/0033339 A1	02/19/04	Fukutani et al.	428	137	
HLL	US 2004/0043208 A1	03/04/04	Fukutani et al.	428	304.4	
HLL	US 2005/0053773 A1	03/10/05	Fukutani et al.	428	209	

FOREIGN PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
HLL	JP 09-0157062 A	06/17/97	Japan			English Translation &
HLL	JP 2001-261376	09/26/01	Japan			English Translation &

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
HLL	C.D. Adams, et al. "Monte Carlo Simulation of Phase Separation During Thin-Film Codeposition," J. Appl. Phys. 74 (3), 1 August 1993, American Institute of Physics, pp. 1707-1715.
HLL	C.D. Adams, et al. "Transition from Lateral to Transverse Phase Separation During Film Co-deposition," Appl. Phys. Lett. 59 (20), 11 November 1991, American Institute of Physics, pp. 2535-2537.
HLL	C.D. Adams, et al. "Phase Separation During Co-deposition of Al-Ge Thin Films," J. Mater. Res., Vol. 7, No. 3, March 1992, Materials Research Society, pp. 653-667.
HLL	M. Atzmon, et al. "Phase Separation During Film Growth," J. Appl. Phys. 42 (2), 15 July 1992, American Institute of Physics, pp. 442-446.
HLL	M. Jacobs, et al. "Unbalanced Magnetron Sputtered Si-Al Coatings: Plasma Conditions and Film Properties Versus Sample Bias Voltage," Surface and Coatings Technology 116-119 (1999) pp. 735-741.

EXAMINER <i>H. D. L.</i>	DATE CONSIDERED <i>9/26/05</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
HU	6,027,796	2/2000	Kondoh et al.	428	312.8		

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